

November 2013

## **FQP16N25**

# N-Channel QFET<sup>®</sup> MOSFET 250 V, 16 A, 230 m $\Omega$

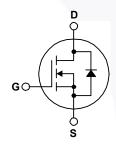
### **Description**

This N-Channel enhancement mode power MOSFET is produced using Fairchild Semiconductor's proprietary planar stripe and DMOS technology. This advanced MOSFET technology has been especially tailored to reduce on-state resistance, and to provide superior switching performance and high avalanche energy strength. These devices are suitable for switched mode power supplies, active power factor correction (PFC), and electronic lamp ballasts.

#### **Features**

- 16 A, 250 V,  $R_{DS(on)}$  = 230 m $\Omega$  (Max.) @  $V_{GS}$  = 10 V,  $I_D$  = 8.0 A
- · Low Gate Charge (Typ. 27 nC)
- · Low Crss (Typ. 23 pF)
- · 100% Avalanche Tested





## Absolute Maximum Ratings T<sub>C</sub> = 25°C unless otherwise noted.

Symbol	Parameter		FQP16N25	Unit	
V <sub>DSS</sub>	Drain-Source Voltage		250	V	
I <sub>D</sub>	Drain Current - Continuous (T <sub>C</sub> = 25°C)		16	A	
	- Continuous (T <sub>C</sub> = 100	)°C)	10	А	
I <sub>DM</sub>	Drain Current - Pulsed	(Note 1)	64	Α	
V <sub>GSS</sub>	Gate-Source Voltage		± 30	V	
E <sub>AS</sub>	Single Pulsed Avalanche Energy	(Note 2)	560	mJ	
I <sub>AR</sub>	Avalanche Current	(Note 1)	16	A	
E <sub>AR</sub>	Repetitive Avalanche Energy (Note 1		14.2	mJ	
dv/dt	Peak Diode Recovery dv/dt (Note 3)		5.5	V/ns	
$P_D$	Power Dissipation (T <sub>C</sub> = 25°C)		142	W	
	- Derate above 25°C		1.14	W/°C	
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Temperature Range		-55 to +150	°C	
T <sub>L</sub>	Maximum Lead Temperature for Soldering, 1/8" from Case for 5 seconds		300	°C	

## **Thermal Characteristics**

Symbol	Parameter	FQP16N25	Unit
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case, Max.	0.88	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient, Max.	62.5	°C/W

## **Package Marking and Ordering Information**

Part Number	Top Mark	Package	Packing Method	Reel Size	Tape Width	Quantity
FQP16N25	FQP16N25	TO-220	Tube	N/A	N/A	50 units

FI	octrica	I Chara	cteristics
	ecu ica	ı Gilala	LIGHISHUS

Symbol	Parameter	Test Conditions	Min	Тур	Max	Unit
Off Cha	aracteristics					
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	V <sub>GS</sub> = 0 V, I <sub>D</sub> = 250 μA	250			V
$\Delta BV_{DSS}$ / $\Delta T_J$	Breakdown Voltage Temperature Coefficient	I <sub>D</sub> = 250 μA, Referenced to 25°	C	0.22		V/°C
I <sub>DSS</sub>	Zero Osto Veltoro Broin Ormant	V <sub>DS</sub> = 250 V, V <sub>GS</sub> = 0 V			1	μΑ
	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 200 V, T <sub>C</sub> = 125°C			10	μΑ
I <sub>GSSF</sub>	Gate-Body Leakage Current, Forward	V <sub>GS</sub> = 30 V, V <sub>DS</sub> = 0 V			100	nA
I <sub>GSSR</sub>	Gate-Body Leakage Current, Reverse	V <sub>GS</sub> = -30 V, V <sub>DS</sub> = 0 V			-100	nA
On Cha	aracteristics		·			
V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	3.0		5.0	V
R <sub>DS(on)</sub>	Static Drain-Source On-Resistance	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 8.0 A		0.18	0.23	Ω
g <sub>FS</sub>	Forward Transconductance	V <sub>DS</sub> = 50 V, I <sub>D</sub> = 8.0 A		18		S
C <sub>iss</sub> C <sub>oss</sub> C <sub>rss</sub>	Input Capacitance Output Capacitance Reverse Transfer Capacitance	$V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V},$ f = 1.0 MHz		920 190 23	1200 250 30	pF pF pF
				23	30	þΓ
	ing Characteristics					
t <sub>d(on)</sub>	Turn-On Delay Time	V <sub>DD</sub> = 125 V, I <sub>D</sub> = 16 A,		17	45	ns
t <sub>r</sub>	Turn-On Rise Time	$R_G = 25 \Omega$		140	290	ns
t <sub>d(off)</sub>	Turn-Off Delay Time	(Note	4)	45	100	ns
t <sub>f</sub>	Turn-Off Fall Time	,		75	160	ns
Qg	Total Gate Charge	$V_{DS} = 200 \text{ V}, I_{D} = 16 \text{ A},$		27	35	nC
Q <sub>gs</sub>	Gate-Source Charge	V <sub>GS</sub> = 10 V		5.8		nC
Q <sub>gd</sub>	Gate-Drain Charge	(Note	4)	15		nC
Drain-S	Source Diode Characteristics a	nd Maximum Ratings				
I <sub>S</sub>	Maximum Continuous Drain-Source Diode Forward Current				16	Α
I <sub>SM</sub>	Maximum Pulsed Drain-Source Diode Forward Current				64	Α
V <sub>SD</sub>	Drain-Source Diode Forward Voltage	V <sub>GS</sub> = 0 V, I <sub>S</sub> = 16 A			1.5	V
t <sub>rr</sub>	Reverse Recovery Time	V <sub>GS</sub> = 0 V, I <sub>S</sub> = 16 A,		190		ns
_	·	11 / 11 / 100 4 /				

## $Q_{rr}$

- **Notes:** 1. Repetitive Rating : Pulse width limited by maximum junction temperature. 2. L = 3.5 mH, I $_{AS}$  = 16 A, V $_{DD}$  = 50 V, R $_{G}$  = 25  $\Omega$ , starting T $_{J}$  = 25°C. 3. I $_{SD}$  ≤ 16 A, di/dt ≤ 300 A/µs, V $_{DD}$  ≤ BV $_{DSS}$ , starting T $_{J}$  = 25°C. 4. Essentially independent of operating temperature.

Reverse Recovery Charge

μС

1.2

 $dI_F / dt = 100 A/\mu s$ 

## **Typical Characteristics**

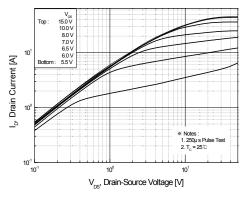


Figure 1. On-Region Characteristics

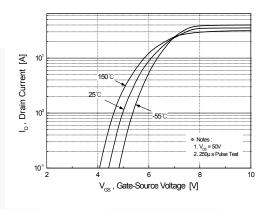


Figure 2. Transfer Characteristics

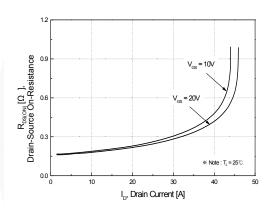


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

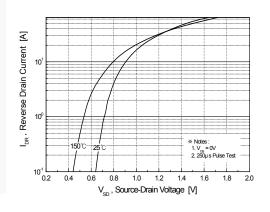


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

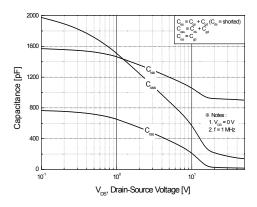


Figure 5. Capacitance Characteristics

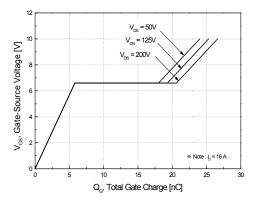
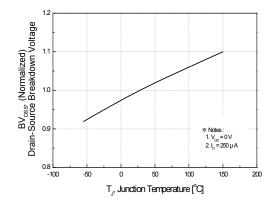


Figure 6. Gate Charge Characteristics

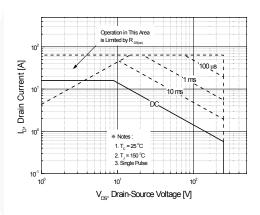
## Typical Characteristics (continued)



25 (Normalized) 20 (Normalized

Figure 7. Breakdown Voltage Variation vs. Temperature

Figure 8. On-Resistance Variation vs. Temperature



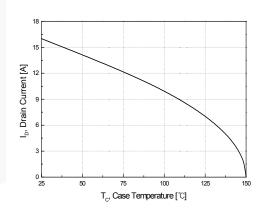


Figure 9. Maximum Safe Operating Area

Figure 10. Maximum Drain Current vs. Case Temperature

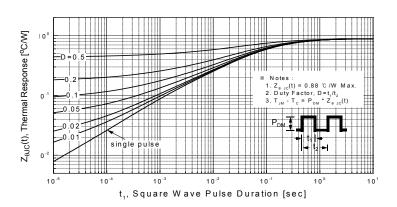


Figure 11. Transient Thermal Response Curve

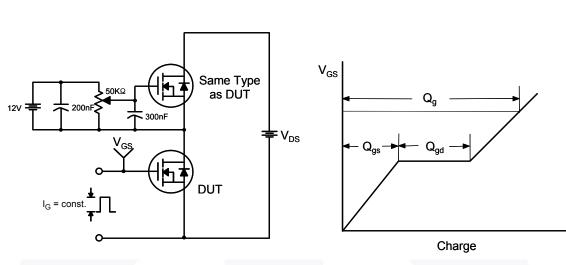


Figure 12. Gate Charge Test Circuit & Waveform

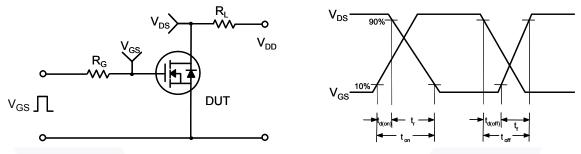


Figure 13. Resistive Switching Test Circuit & Waveforms

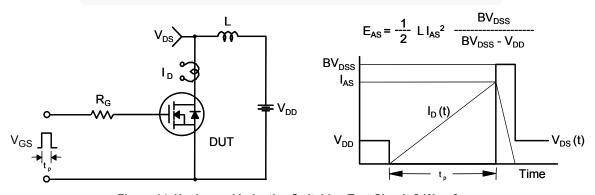
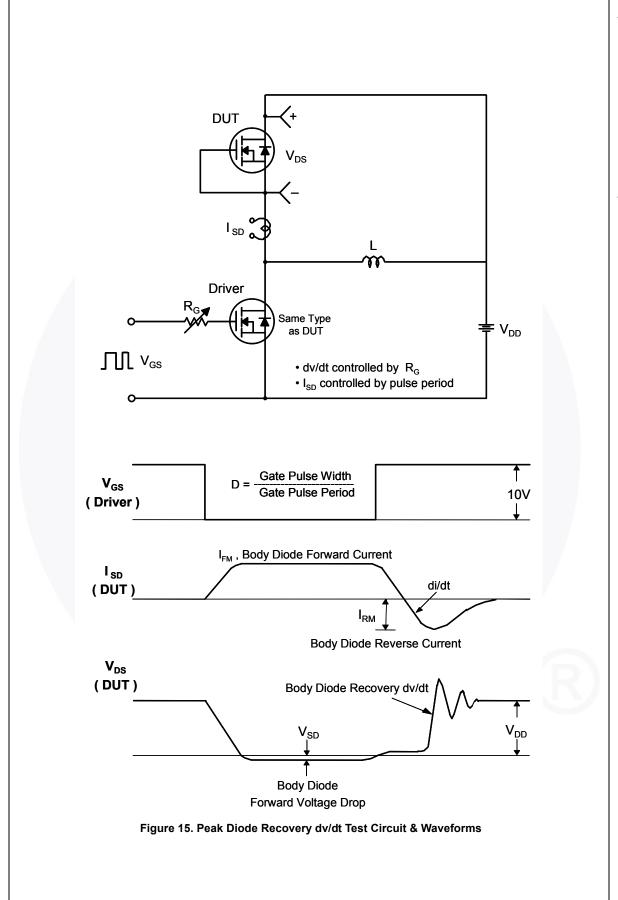
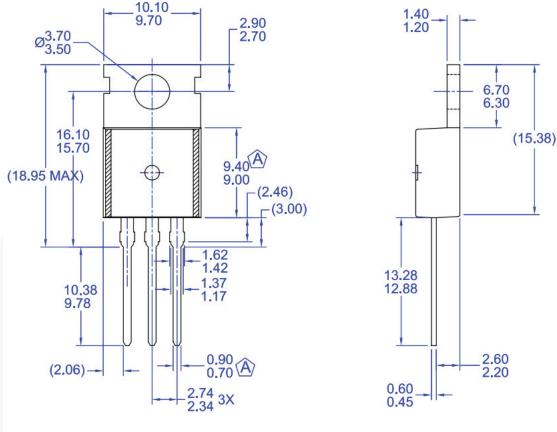


Figure 14. Unclamped Inductive Switching Test Circuit & Waveforms



## **Mechanical Dimensions**



4.70 10.20

9.80

#### NOTES:

- (A) CONFORMS TO JEDEC TO-220 VARIATION AB EXCEPT WHERE NOTED
- B) ALL DIMENSIONS ARE IN MILLIMETERS.
- C) DIMENSIONS ARE EXCLUSIVE OF BURRS, MOLD FLASH, AND TIE BAR EXTRUSIONS.
- D) DRAWING FILE/REVISION: MKT-TO220Y03REV1

Figure 16. TO220, Molded, 3-Lead, Jedec Variation AB

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